

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/551,655	AYABE, SHINICHI	
Examiner	Art Unit	
VONC D. DAK	4050	

	SEARCHED				
Class	Subclass	Date	Examiner		

INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
435	232	8/28/2008	YP	
435	69.1	8/28/2008	YP	
536	23.2	8/28/2008	YP	
seq id no:3 and 4		8/28/2008	ΥP	

SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
stic: seq id no:3 and 4, see score	8/28/2008	YP		
EAST (all databases): text and inventor search, see search history	8/30/2008	YP		
PALM: inventor search	8/28/2008	YP		